



IMEKO

International Measurement Confederation

Technical
Committee
TC10
Technical Diagnostics

CALL FOR PAPERS

General Chair

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Important deadlines

1st April, 2014

Deadline for extended
abstracts submission

30th April, 2014

Notification about the papers
acceptance

1st June, 2014

Deadline for camera-ready
papers

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INVITATION

The International Measurement Confederation IMEKO, Technical Committee 10 – Technical Diagnostics, is proud to invite you to attend the 13th **IMEKO TC10 Workshop on Technical Diagnostics – “Advanced measurement tools in technical diagnostics for systems' reliability and safety”** to be held in Warsaw, Poland, on June 26-27, 2014. The Workshop is a forum for exchanging knowledge and share ideas or solutions regarding methods, principles, instruments and tools, standards and industrial applications on Technical Diagnostics, including their diffusion across the scientific community. Participants will have the excellent opportunity to exchange scientific and technical experience with specialists from around the world and to start or expand their international co-operation.

CALL FOR PAPERS

Authors are kindly invited to submit extended summaries on the topics listed below, three to four pages length in A4 format. The abstract should report on original research results of theoretical or applied nature, explaining the significance of the contribution to the research field. The summaries will be reviewed by the International Program Committee. Electronic summaries must be in Adobe Acrobat (pdf) and should be sent according to the procedure described on the conference website: <http://www.imekotc10-2014.org>.

SPECIAL ISSUE

The IMEKO TC10 Special Issue will contain selected papers on the basis of the results of regular peer review of the manuscripts submitted. The manuscript **MUST** be significantly extended beyond the scope of the proceedings paper. The selected papers will be published in the Measurement (Elsevier), Metrology and Measurement Systems and ACTA IMEKO journals.

TOPICS

- basic principles and development trends in technical diagnostics
- on-line condition monitoring and maintenance of industrial process, plants and complex systems
- advanced sensors, data acquisition systems and signal processing for diagnostic tasks
- technical identification and prediction models
- safety critical systems
- diagnostics for Maintainability, Safety, Risk assessment and management
- model-based diagnostics
- non-destructive testing
- artificial intelligence techniques and machine learning for diagnostics
- diagnostics applications in transportation, mechatronics, avionics, automotive and biomedical systems
- decision support and IT solutions for diagnosis
- diagnostics for the improvement of quality of life and environment
- standards of industrial systems and processes diagnostics
- industrial applications of monitoring and supervision systems

